

Search Notes

Application/Control No.

10/773,179

Examiner

Emmanuel Bayard

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	260	8/4/2007	EB
375	261	8/4/2007	EB
375	285	8/4/2007	EB
375	295	8/4/2007	EB
375	296	8/4/2007	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	295	8/4/2007	EB
375	286	8/4/2007	EB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	8/4/2007	EB